

10-567346

IAP9 Rec'd PCT/PTO 06 FEB 2006

6
3

Enclosure: PTO/SB/08, 5 documents and international search report.

Combined Form PTO/SB/08A&B <u>INFORMATION DISCLOSURE</u> <u>STATEMENT BY APPLICANT</u> <i>(use as many sheets as necessary)</i>				<i>Complete if Known</i>	
				Application Number	New Application
				Confirmation Number	
				Filing Date	February 6, 2006
				First Named Inventor	Hideki NINOMIYA et al.
				Art Unit	
Examiner Name				Attorney Docket Number	062088
Sheet	1	of	1		

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Document Number		Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document
		Number	Kind Code ² (if known)		
/LGL/	1	US 4,573,792		03-04-1986	Koichi KAJIYAMA et al.
/LGL/	2	US 2002/0118352		08-29-2002	Akira OHZU et al.
		US			
		US			
		US			
		US			
		US			

FOREIGN PATENT DOCUMENTS							
Examiner Initials*	Cite No. ¹	Foreign Patent Document			Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Translation ⁶
		Country Code ³	Number ⁴	Kind Code ⁵ (if known)			
	3	JP	49-100997		09-24-1974	Noumi Disaster Prevention Mfg. Co., Ltd.	Abstract, cited in the ISR
/LGL/	4	JP	59-10835		01-20-1984	Komatsu Ltd.	Abstract, cited in the ISR
/LGL/	5	JP	6-288858		10-18-1994	Osaka Gas Co., Ltd.	Abstract, cited in the ISR
/LGL/	6	JP	9-178566		07-11-1997	Tokai Carbon Co., Ltd.	Abstract, cited in the ISR

NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city, and/or country where published.	Translation ⁶
/LGL/	7	W. A. de GROOT; "The Use of Spontaneous Raman Scattering for Hydrogen Leak Detection" 30 th AIAA/ASME/SAE/ASEE Joint Propulsion Conference, June 27-29, 1994, pp.1-11. Cited in the International Search Report.	
/LGL/	8	International Search Report, dated July 27, 2004 of PCT/JP2004/008038	

Examiner Signature	/Layla G. Lauchman/	Date Considered	09/11/2008
--------------------	---------------------	-----------------	------------

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹Applicant's unique citation designation number (optional). ²See Kind Codes of USPTO Patent Documents at www.uspto.gov, MPEP 901.04 or in the comment box of this document. ³Enter Office that issued the document, by the two-letter code (WIPO Standard ST. 3). ⁴For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶Applicant is to indicate here if English language Translation is attached.